

# TL5632C

## 8-BIT 3-CHANNEL HIGH-SPEED DIGITAL-TO-ANALOG CONVERTER

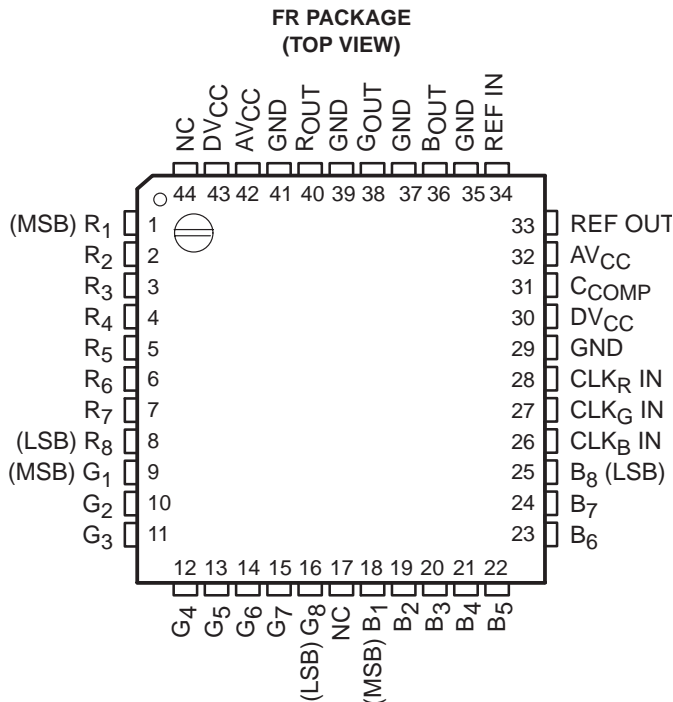
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- **8-Bit Resolution**
- **Linearity . . .  $\pm 1/2$  LSB Maximum**
- **Differential Nonlinearity . . .  $\pm 1/2$  LSB Maximum**
- **Conversion Rate . . . 60 MHz Min**
- **Nominal Output Signal Operating Range  $V_{CC}$  to  $V_{CC} - 1$  V**
- **TTL Digital Input Voltage**
- **5-V Single Power Supply Operation**
- **Low Power Consumption . . . 350 mW Typ**

### description

The TL5632C is a low-power ultra-high-speed video digital-to-analog converter that uses the Advanced Low-Power Schottky (ALS) process. The device has a three channel I/O; the red, the blue, and the green channel. The red, blue, and green signals are referred to collectively as the RGB signal. An internally generated reference is also provided for the standard video output voltage range. Conversion of digital signals to analog signals can be at a sampling rate of dc to 60 MHz. The high conversion rate makes the TL5632C suitable for digital television, computer digital video processing, and high-speed data conversion.

The TL5632C is characterized for operation from 0°C to 70°C.



NC – No internal connection

**FUNCTION TABLE**

STEP	DIGITAL INPUT	OUTPUT VOLTAGE
0	LLLLLLLLL	3.980 V
1	LLLLLLLLH	3.984 V
•	•	•
•	•	•
•	•	•
127	LHHHHHHH	4.488 V
128	HLLLLLLL	4.492 V
129	HLLLLLLH	4.996 V
•	•	•
•	•	•
•	•	•
254	HHHHHHHL	4.996 V
255	HHHHHHH	5.000 V

**AVAILABLE OPTIONS**

T <sub>A</sub>	PACKAGE
0°C to 70°C	TL5632CFR

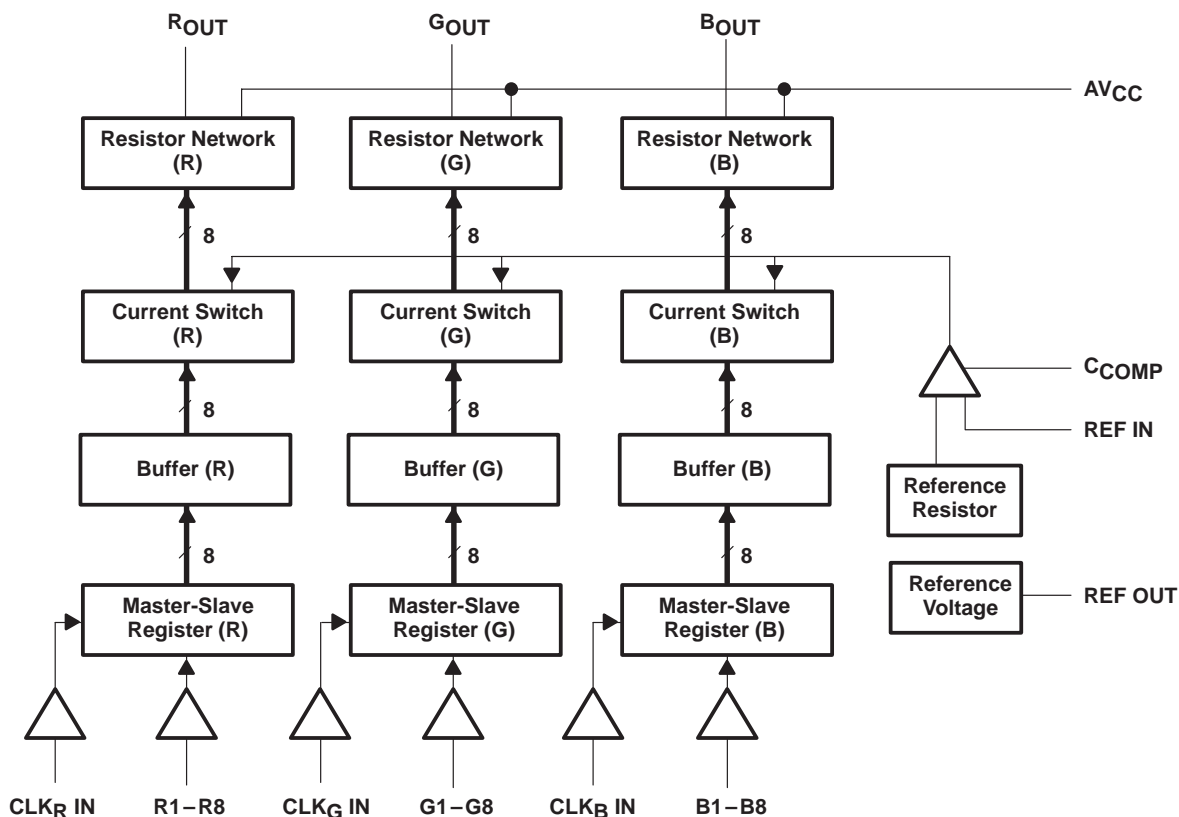
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



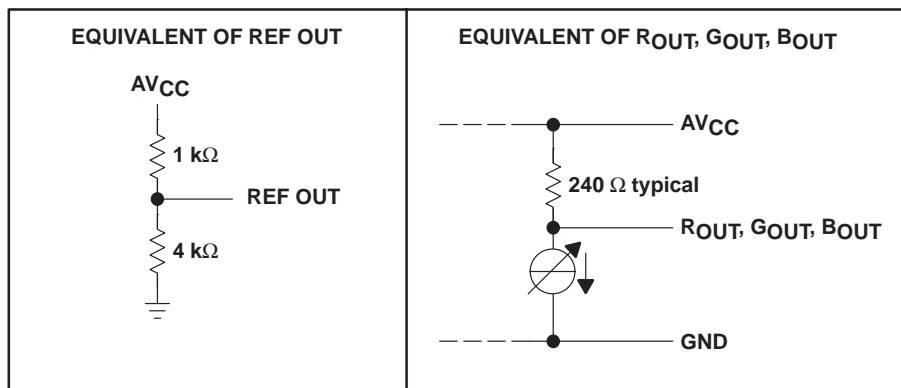
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## functional block diagram



## schematics of outputs



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### Terminal Functions

TERMINAL NAME	NO.	I/O	DESCRIPTION
B <sub>1</sub> – B <sub>8</sub>	18 – 25	I	B-channel digital input (B <sub>1</sub> = MSB)
B <sub>OUT</sub>	36	O	B-channel analog output
C <sub>COMP</sub>	31		Phase compensation capacitance. A 1 μF capacitor is connected from C <sub>COMP</sub> to GND.
CLK <sub>B</sub> IN	26	I	B-channel clock input
CLK <sub>G</sub> IN	27	I	G-channel clock input
CLK <sub>R</sub> IN	28	I	R-channel clock input
G <sub>1</sub> – G <sub>8</sub>	9 – 16	I	G-Channel digital input (G <sub>1</sub> = MSB)
GND	29, 35, 37, 39, 41		Ground. All GND terminals are connected internally; however, all GND terminals should be connected externally to a ground plane or equivalent low impedance ground return.
G <sub>OUT</sub>	38	O	G-channel analog output
NC	17, 44		No connection internally
R <sub>1</sub> – R <sub>8</sub>	1 – 8	I	R-channel digital input (R <sub>1</sub> = MSB)
R <sub>OUT</sub>	40	O	R-channel analog output
AV <sub>CC</sub>	32, 42		Analog power supply voltage
DV <sub>CC</sub>	30, 43		Digital power supply voltage
REF IN	34	I	Reference voltage input. REF IN accepts the reference voltage on REF OUT. An external reference can also be applied consistent with Note 1.
REF OUT	33	O	Reference voltage output. An internal voltage divider generates the voltage level (see schematics of outputs, page 2).

NOTE 1:  $V_{CC} - V_{ref} \leq 1.2 \text{ V}$

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Power supply voltage range, AV <sub>CC</sub> , DV <sub>CC</sub> (see Note 2)	–0.3 V to 7 V
Digital input voltage range, V <sub>I</sub>	–0.3 V to DV <sub>CC</sub>
Analog output voltage range, R <sub>OUT</sub> , G <sub>OUT</sub> , B <sub>OUT</sub> , C <sub>COMP</sub> (externally applied)	–0.3 V to AV <sub>CC</sub> + 0.3 V
Reference input range, REF IN	–0.3 V to AV <sub>CC</sub> + 0.3 V
Reference output range, REF OUT	–0.3 V to AV <sub>CC</sub> + 0.3 V
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 2: All voltage values are with respect to GND.



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### recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, $V_{CC}$ , $DV_{CC}$	4.75	5	5.25	V
High-level input voltage, $V_{IH}$	2			V
Low-level input voltage, $V_{IL}$			0.8	V
Reference voltage, $V_{ref}$ (see Note 1)	3.8	4	4.2	V
Setup time, data before $CLK\uparrow$ , $t_{su1}$	10			ns
Hold time, data after $CLK\uparrow$ , $t_{h1}$	3			ns
Pulse duration at high level, $t_{w1}$	8.3			ns
Pulse duration at low level, $t_{w2}$	8.3			ns
External phase compensation capacitance, $C_{COMP}$	1			$\mu F$
Operating free-air temperature, $T_A$	0		70	$^{\circ}C$

NOTE 1:  $V_{CC} - V_{ref} \leq 1.2 V$

### electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
Resolution				8	Bit
$I_{IH}$	High-level input current $V_{CC} = 5.25 V$ , $V_{IH} = 2.7 V$			20	$\mu A$
$I_{IL}$	Low-level input current $V_{CC} = 5.25 V$ , $V_{IH} = 2.7 V$	-400			$\mu A$
$I_{ref}$	Reference input current REF IN = 4 V			10	$\mu A$
$V_{ref}$	Reference output voltage $V_{CC} = 5 V$ , With internal reference	3.8	4	4.2	V
$V_{FS}$	Full-scale analog output voltage $V_{IH} = 2 V$ , REF IN = 4 V	$AV_{CC} - 15$	$AV_{CC}$	$AV_{CC} + 15$	mV
$V_{ZS}$	Zero-scale analog output voltage $V_{IL} = 0.8 V$ , REF IN = 4 V	3.9	3.98	4.05	V
RGB full-scale ratio		0%	4%	8%	
$z_o$	Output impedance	200	240	280	$\Omega$
$I_{CC}$	Supply current		70	90	mA

### operating characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
$E_L$	Linearity error End point, REF IN = 4 V			$\pm 0.5$	LSB
$E_D$	Differential linearity error REF IN = 4 V			$\pm 0.5$	LSB
$f_c$	Maximum conversion rate		60		MHz
$t_{PLH}$	Propagation delay time, low-to-high level		10		ns
$t_{PHL}$	Propagation delay time, high-to-low level		10		
$t_r$	Rise time		5		ns
$t_f$	Fall time		5		

† All typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25^{\circ}C$ .

‡  $C_L$  includes probe and jig capacitances.

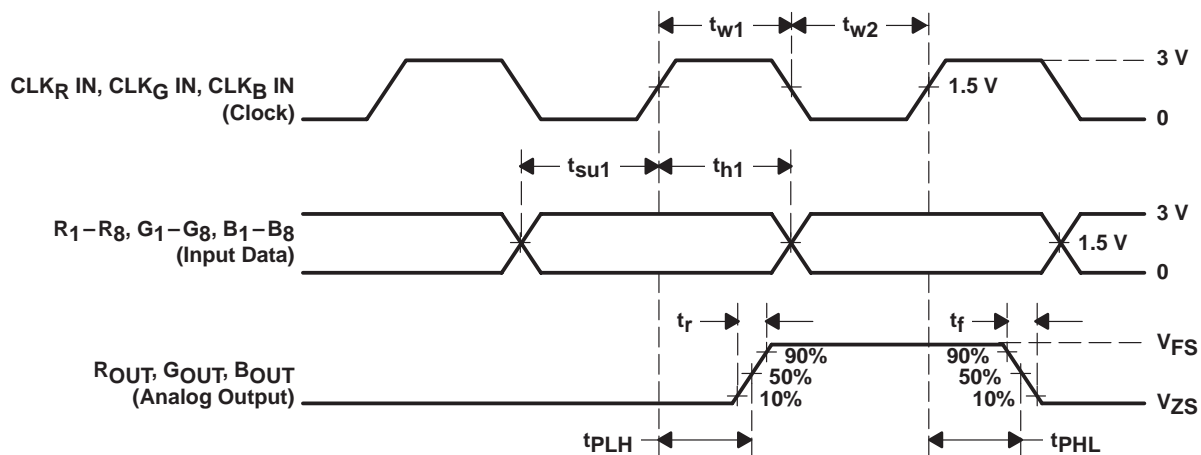


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### PARAMETER MEASUREMENT INFORMATION



### TYPICAL CHARACTERISTICS

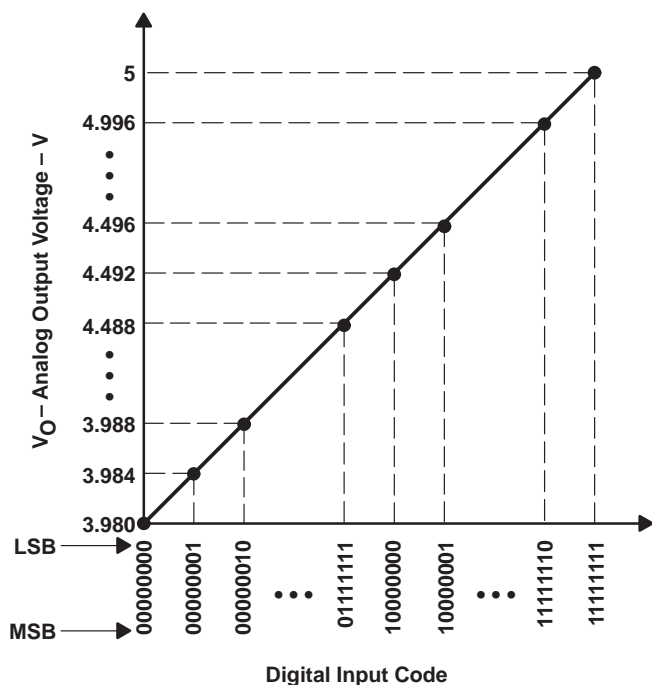


Figure 1. Ideal Conversion Characteristics

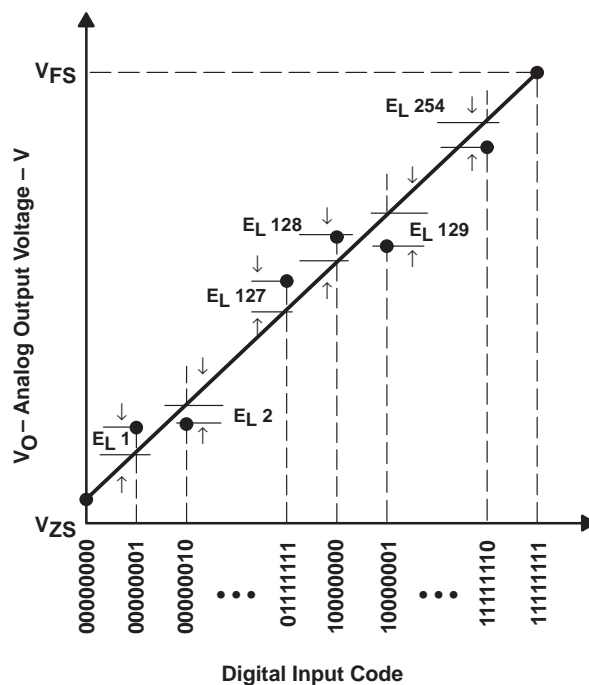


Figure 2. End-Point Linearity Error



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### APPLICATION INFORMATION

The following design procedures should be used for optimum operation.

- External analog and digital circuitry should be physically separated and shielded as much as possible to reduce system noise.
- RF breadboarding or RF printed-circuit-board (PCB) techniques should be used throughout the evaluation and production process.
- Wide ground leads or a ground plane should be used on the PCB layouts to minimize parasitic inductance and resistance. A ground plane is the better choice for noise reduction.
- $AV_{CC}$  and  $DV_{CC}$  are also separate internally, so they must be connected externally. These external PCB leads should also be made as wide as possible. A ferrite bead or equivalent inductance should be placed in series with  $AV_{CC}$  and the decoupling capacitor before the  $AV_{CC}$  and  $DV_{CC}$  leads are connected together on the board. It is critical that the supply voltage applied to  $AV_{CC}$  be as noise free and ripple free as possible. Ripple and noise rejection should be a minimum of 60 dB below the full-scale output range of 1 V peak-to-peak.
- $AV_{CC}$  to GND and  $DV_{CC}$  to GND should be decoupled with 3.3- $\mu$ F and 0.1- $\mu$ F capacitors, respectively, as close as possible to the appropriate device terminals. A ceramic chip capacitor is recommended for the 0.1- $\mu$ F capacitor.
- The phase compensation capacitor should be connected between  $C_{COMP}$  and GND with as short a lead-in as possible.
- The no-connection (NC) terminals on the small-outline package should be connected to GND.
- $AV_{CC}$ ,  $DV_{CC}$ , and  $R_{OUT}$ ,  $G_{OUT}$ , and  $B_{OUT}$  should be shielded from the high-frequency terminals  $CLK_R IN$ ,  $CLK_G IN$ , and  $CLK_B IN$  and the input data terminals. GND traces should be placed on both sides of the  $R_{OUT}$ ,  $G_{OUT}$ , and  $B_{OUT}$  traces on the PCB to the following signal processing stage. These output traces should be as short as possible.



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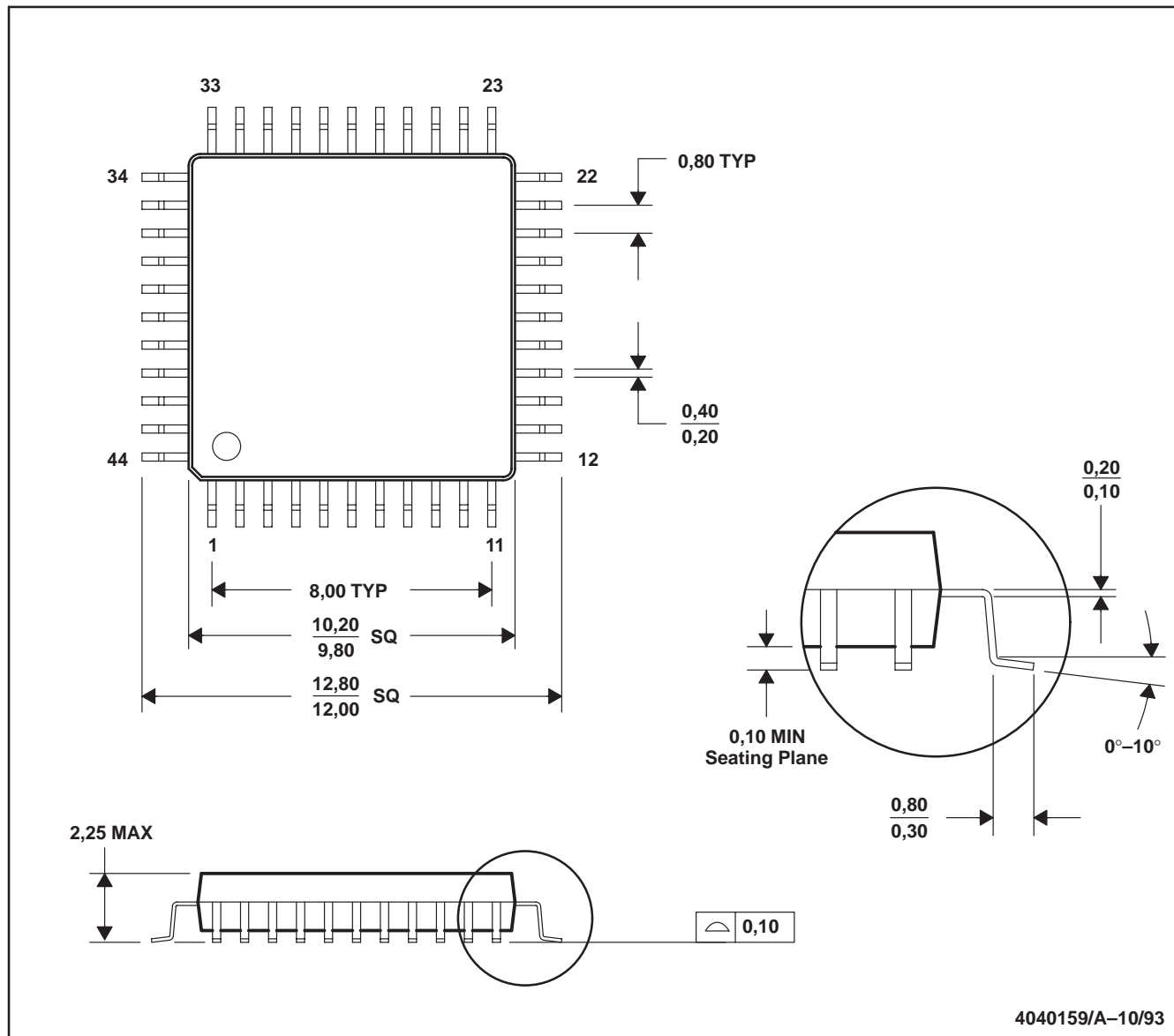
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## MECHANICAL DATA

FR/S-PQFP-G44

PLASTIC QUAD FLATPACK



4040159/A-10/93

NOTES: A. All linear dimensions are in millimeters.  
B. This drawing is subject to change without notice.



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